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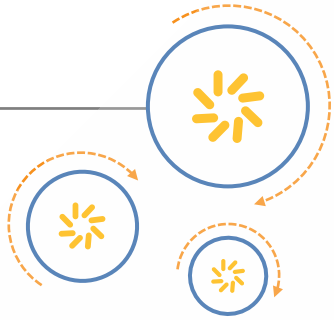
Effective June 2016, Qualcomm Atheros, Inc. (QCA) transferred certain of its assets, including substantially all of its products and services, to its parent corporation, Qualcomm Technologies, Inc. Qualcomm Technologies, Inc. is a wholly-owned subsidiary of Qualcomm Incorporated. Accordingly, references in this document to Qualcomm Atheros, Inc., Qualcomm Atheros, Atheros, QCA or similar references, should properly reference, and shall be read to reference, Qualcomm Technologies, Inc.

Qualcomm Atheros, Inc.



QCA8075

Device Revision Guide

80-Y9112-3 Rev. E

December 7, 2015

For additional information or to submit technical questions go to https://createpoint.qti.qualcomm.com/

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Revision history

Revision	Date	Description
A	July 2015	Initial release
B	July 2015	Updated Issues – description, impact, and workaround
C	September 2015	Updated section 2.2 and chapter 3 for QCA8075 1.1 ES
D	November 2015	Updated date code in 2.2 Device identification for each sample type
E	December 2015	Added I-temp CS details in 2.2 Device identification for each sample type

1 Introduction

Technical information for the QCA8075 device is primarily covered by the documents listed in Table 1.

Table 1 Primary QCA8075 documents

Document number	Documentation title
80-Y9112-1	*QCA8075 Five-Port 10/100/1000 Mbps Ethernet Transceiver Preliminary Device Specification*
80-Y9112-2	*QCA8075 Five-Port 10/100/1000 Mbps Ethernet Transceiver Hardware Programming Reference*
80-Y9112-3 (this document)	*QCA8075 Device Revision Guide*

1.1 Scope and intended audience

This device revision guide identifies issues with all QCA8075 samples released to date. The following information is included:

- Introduction to this document and its topic (Chapter 1)
- Device identification (Chapter 2)
  - Device marking
  - Identification details for each sample type
  - Sample testing (ES and CS explanations)
- Known issues (Chapter 3)
  - Issue description
  - Impact to system performance
  - Possible workarounds (what designers should do to minimize the issue's impact)

This device revision guide is intended for new product developers who are designing, testing, and/or evaluating products that include the QCA8075 device.

2 Device Identification

The QCA8075 device can be identified by the markings on its top surface and by the contents of an identification register; these identification techniques are described in Section 2.1 through Section 2.2.

2.1 Device marking

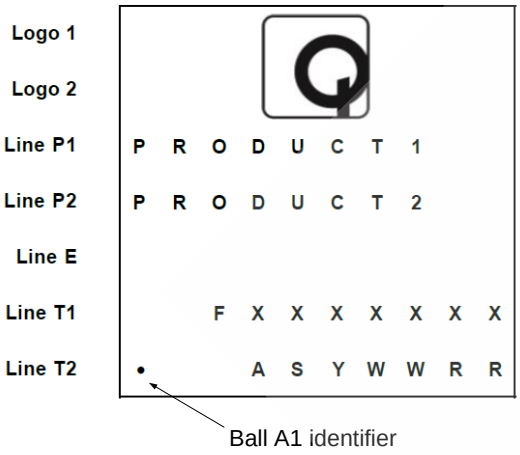

Figure 1 Device marking (top view, not to scale)

Table 2 Device marking line definitions

Line	Marking	Description
Logo 1 and 2	QUALCOMM	Qualcomm Atheros name or logo
P1	QCA8075	Qualcomm Atheros product name
P2	PAA	P = product configuration code AA = product feature code
E[1]		Blank space between P2 and T1
T1	FXXXXXXX	F = source of supply code XXXXXXX = wafer lot ID
T2	ASYWWRR	A = assembly site code S = assembly sequence number Y = single, last digit of year WW = work week (based on calendar year) RR = product revision

1. Line E may appear on the part marking for some samples. This is manufacturing information that is only relevant to Qualcomm and Qualcomm suppliers.

2.2 Device identification for each sample type

Table 3 Device identification details

Device	Product configuration code (P)	Product revision (RR)	Feature code (AA)	Sample type	Year/work week	Operating temperature (ambient)
QCA8075	0	00	VV	ES	≥1529	0 to 70°C
QCA8075	1	00	VV	ES	≥1529	-40 to 85°C
QCA8075	0	01	VV	CS	≥1546[1]	0 to 70°C
QCA8075	1	01	VV	CS	≥1546	-40 to 85°C

NOTE: 1. Lot number 100PEP3019.U1U10 with date code 1538 is also CS material.

2.3 Sample testing

The “Sample type” codes in Table 3 are defined below.

2.3.1 Engineering samples (ES)

These devices have undergone limited testing and sometimes have significant feature limitations. They are suitable to assist with PCB development, conduct board-level electrical evaluation tests, and explore manufacturing considerations.

2.3.2 Commercial samples (CS)

These devices have undergone full production-level testing and meet the specifications and features described in the device specification, except as otherwise noted in this document. They have passed device-level qualification. Commercial samples are suitable to be used for performance testing, and also product-level production and qualification.

3 Known Issues

None